

Search Notes

Application/Control No.

10/776,433

Examiner

Patricia Leith

Applicant(s)/Patent under
Reexamination

REN ET AL.

Art Unit

1655

SEARCHED

Class	Subclass	Date	Examiner
424	725	3/3/2006	PL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
424	725	3/3/2006	PL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
updated EAST: JPO,EPO,DERWENT,USPATFULL,U SPGPUBS,OCRBACKFILE	3/3/2006	PL

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
STN: Indexed Bioscience cluster	3/1/2006	PL
consulted parent case	3/1/2006	PL
Inventor name search PALM/EAST	3/6/2006	pl